

**Search Notes**

Application/Control No.

09/922,065

Examiner

Ted M. Wang

Applicant(s)/Patent under  
Reexamination

MAR ET AL.

Art Unit

2634

**SEARCHED**

Class	Subclass	Date	Examiner
324	76.22, 614	12/22/2005	TW
	UPDATED		
375	224, 226	12/22/2005	TW
375	227	12/22/2005	TW
324	76.19	12/22/2005	TW
324	613, 622	12/22/2005	TW

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
375	224, 226	12/22/2005	TW
375	227	12/22/2005	TW
324	613, 614	12/22/2005	TW
324/622, 76.19, 76.22		12/22/2005	TW

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST - USPGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB, see attached search report	12/22/2005	TW
IEEE - Advance search - phase noise measurement and spectrum analyzer	12/22/2005	TW
IEEE- phase noise and (contribute or generate or caused) by spectrum analyzer	12/22/2005	TW
GOOGLE- phase noise and (contribute or generate or caused) and spectrum analyzer	12/22/2005	TW
GOOGLE - Rohde & Schwarz Test and Measurement and phase noise	12/22/2005	TW